

International **IR** Rectifier

**REPETITIVE AVALANCHE AND dv/dt RATED
HEXFET® TRANSISTORS
THRU-HOLE (TO-204AA/AE)**

**IRF250
JANTX2N6766
JANTXV2N6766
[REF:MIL-PRF-19500/543]
200V, N-CHANNEL**

Product Summary

Part Number	BVDSS	RDS(on)	ID
IRF250	200V	0.085Ω	30A

The HEXFET® technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry and unique processing of this latest "State of the Art" design achieves: very low on-state resistance combined with high transconductance; superior reverse energy and diode recovery dv/dt capability.

The HEXFET transistors also feature all of the well established advantages of MOSFETs such as voltage control, very fast switching, ease of paralleling and temperature stability of the electrical parameters.

They are well suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers and high energy pulse circuits.



TO-3

Features:

- Repetitive Avalanche Ratings
- Dynamic dv/dt Rating
- Hermetically Sealed
- Simple Drive Requirements
- Ease of Paralleling

Absolute Maximum Ratings

	Parameter	Units	
ID @ VGS = 10V, TC = 25°C	Continuous Drain Current	A	30
ID @ VGS = 10V, TC = 100°C	Continuous Drain Current		19
IDM	Pulsed Drain Current ①		120
PD @ TC = 25°C	Max. Power Dissipation	W	150
	Linear Derating Factor	W/°C	1.2
VGS	Gate-to-Source Voltage	V	±20
EAS	Single Pulse Avalanche Energy ②	mJ	500
IAR	Avalanche Current ①	A	30
EAR	Repetitive Avalanche Energy ①	mJ	15
dv/dt	Peak Diode Recovery dv/dt ③	V/ns	5.0
TJ	Operating Junction	°C	-55 to 150
TSTG	Storage Temperature Range		
	Lead Temperature		300 (0.063 in. (1.6mm) from case for 10s)
	Weight	g	11.5 (typical)

For footnotes refer to the last page

Electrical Characteristics @ $T_j = 25^\circ\text{C}$ (Unless Otherwise Specified)

Parameter		Min	Typ	Max	Units	Test Conditions
BV _{DSS}	Drain-to-Source Breakdown Voltage	200	—	—	V	$V_{GS} = 0\text{V}, I_D = 1.0\text{mA}$
$\Delta BV_{DSS}/\Delta T_J$	Temperature Coefficient of Breakdown Voltage	—	0.29	—	V/ $^\circ\text{C}$	Reference to 25°C , $I_D = 1.0\text{mA}$
$R_{DS(on)}$	Static Drain-to-Source On-State Resistance	—	—	0.085	Ω	$V_{GS} = 10\text{V}, I_D = 19\text{A}$ ④
		—	—	0.090		$V_{GS} = 10\text{V}, I_D = 30\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
g_{fs}	Forward Transconductance	9.0	—	—	S (mS)	$V_{DS} > 15\text{V}, I_{DS} = 19\text{A}$ ④
I_{DSS}	Zero Gate Voltage Drain Current	—	—	25	μA	$V_{DS} = 160\text{V}, V_{GS} = 0\text{V}$
		—	—	250		$V_{DS} = 160\text{V}$ $V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Leakage Forward	—	—	100	nA	$V_{GS} = 20\text{V}$
I_{GSS}	Gate-to-Source Leakage Reverse	—	—	-100		$V_{GS} = -20\text{V}$
Q_g	Total Gate Charge	55	—	115	nC	$V_{GS} = 10\text{V}, I_D = 30\text{A}$
Q_{gs}	Gate-to-Source Charge	8	—	22		$V_{DS} = 100\text{V}$
Q_{gd}	Gate-to-Drain ('Miller') Charge	30	—	60		
$t_{d(on)}$	Turn-On Delay Time	—	—	35	n s	$V_{DD} = 100\text{V}, I_D = 30\text{A}, R_G = 2.35\Omega$
t_r	Rise Time	—	—	190		
$t_{d(off)}$	Turn-Off Delay Time	—	—	170		
t_f	Fall Time	—	—	130		
$L_{S + LD}$	Total Inductance	—	6.1	—	nH	Measured from the center of drain pad to center of source pad
C_{iss}	Input Capacitance	—	3500	—	pF	$V_{GS} = 0\text{V}, V_{DS} = 25\text{V}$ $f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	—	700	—		
C_{rss}	Reverse Transfer Capacitance	—	110	—		

Source-Drain Diode Ratings and Characteristics

	Parameter	Min	Typ	Max	Units	Test Conditions
I_S	Continuous Source Current (Body Diode)	—	—	30	A	$T_j = 25^\circ\text{C}, I_S = 30\text{A}, V_{GS} = 0\text{V}$ ④
I_{SM}	Pulse Source Current (Body Diode) ①	—	—	120		
V_{SD}	Diode Forward Voltage	—	—	1.9	V	$T_j = 25^\circ\text{C}, I_S = 30\text{A}, V_{GS} = 0\text{V}$ ④
t_{rr}	Reverse Recovery Time	—	—	950	nS	$T_j = 25^\circ\text{C}, I_F = 30\text{A}, dI/dt \leq 100\text{A}/\mu\text{s}$
Q_{RR}	Reverse Recovery Charge	—	—	9.0	μC	$V_{DD} \leq 50\text{V}$ ④
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by $L_{S + LD}$.				

Thermal Resistance

	Parameter	Min	Typ	Max	Units	Test Conditions
R_{thJC}	Junction to Case	—	—	0.83	$^\circ\text{C/W}$	Typical socket mount
R_{thJA}	Junction to Ambient	—	—	30		

For footnotes refer to the last page

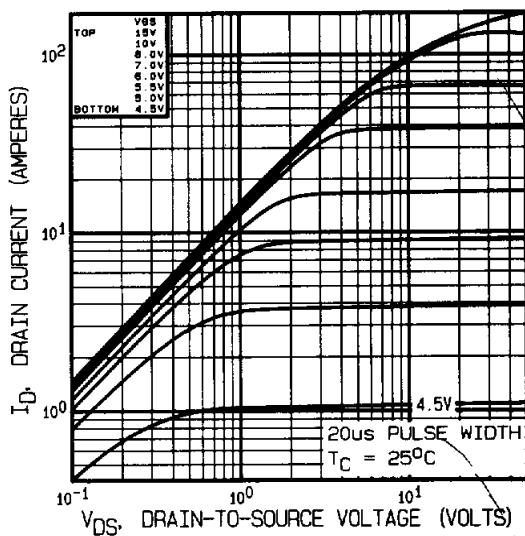


Fig 1. Typical Output Characteristics

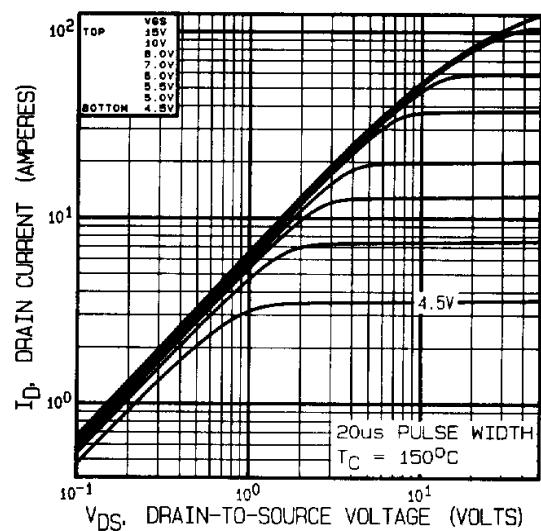


Fig 2. Typical Output Characteristics

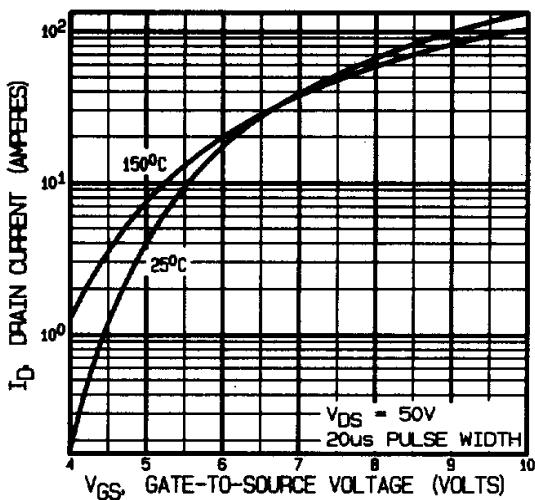


Fig 3. Typical Transfer Characteristics

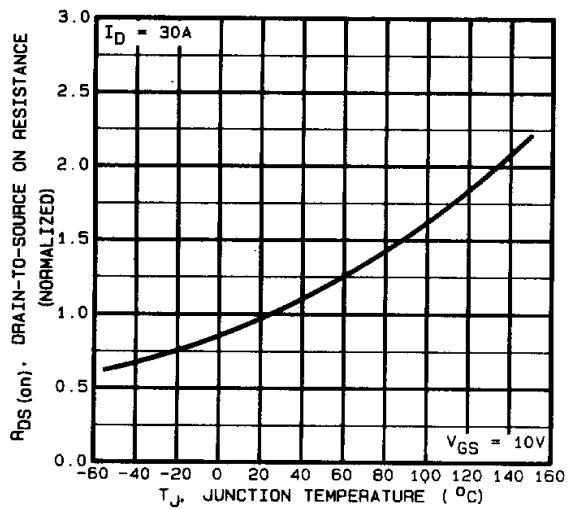


Fig 4. Normalized On-Resistance Vs. Temperature

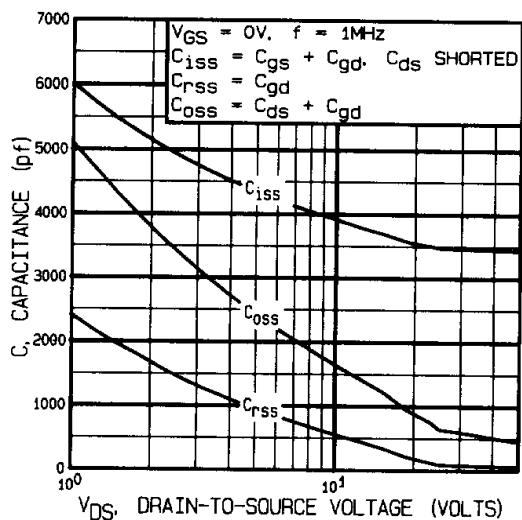


Fig 5. Typical Capacitance Vs.
Drain-to-Source Voltage

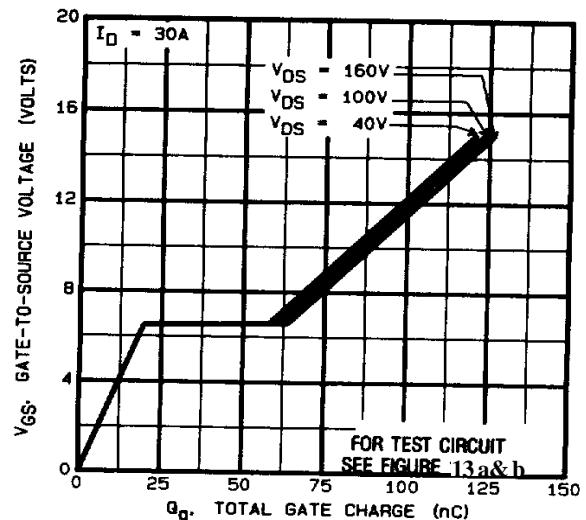


Fig 6. Typical Gate Charge Vs.
Gate-to-Source Voltage

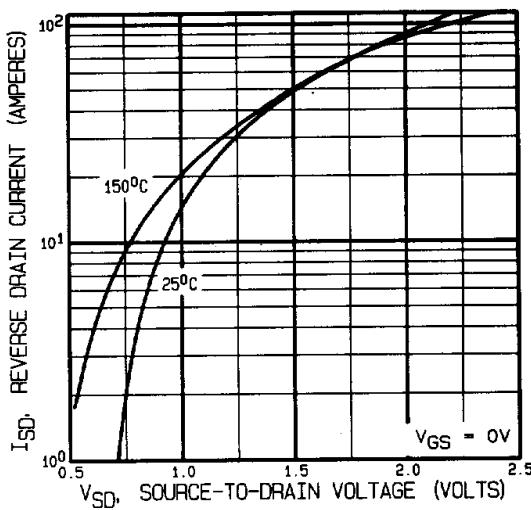


Fig 7. Typical Source-Drain Diode
Forward Voltage

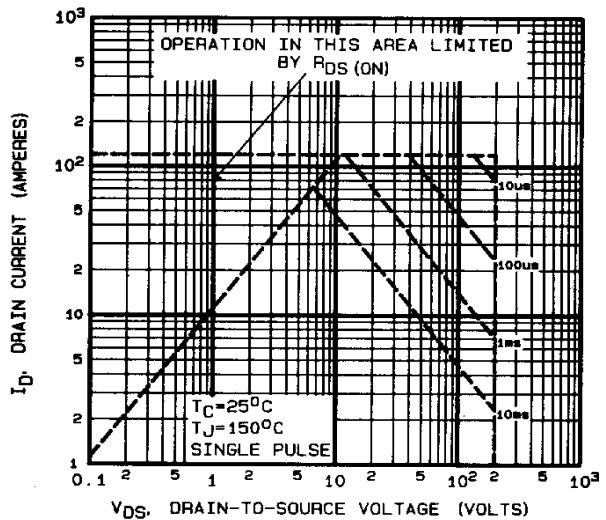


Fig 8. Maximum Safe Operating Area

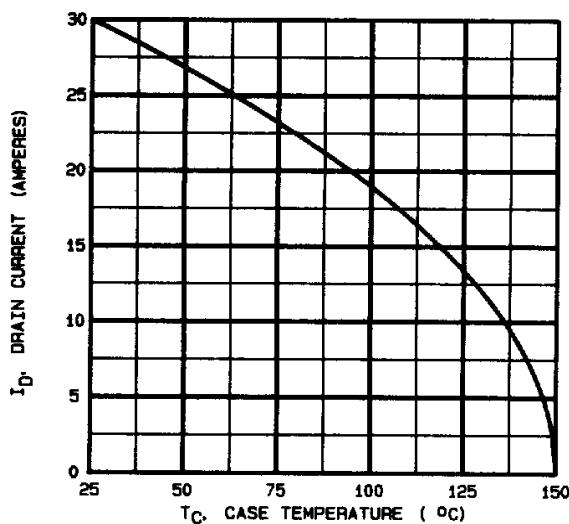


Fig 9. Maximum Drain Current Vs.
Case Temperature

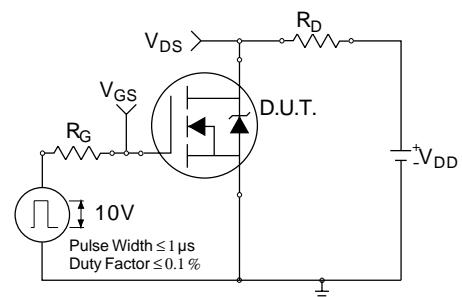


Fig 10a. Switching Time Test Circuit

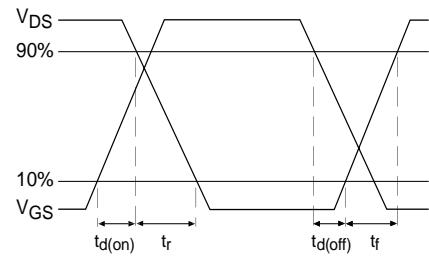


Fig 10b. Switching Time Waveforms

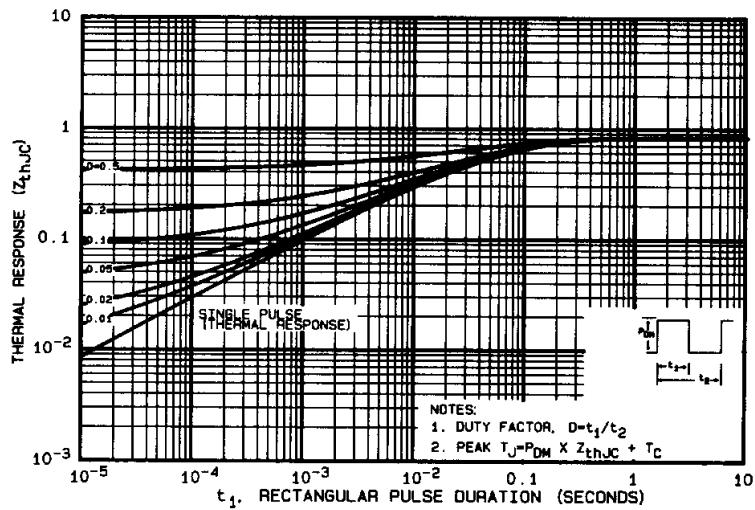


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

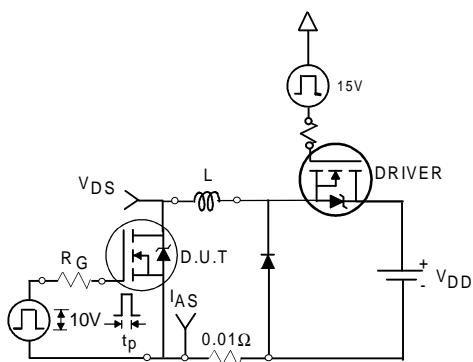


Fig 12a. Unclamped Inductive Test Circuit

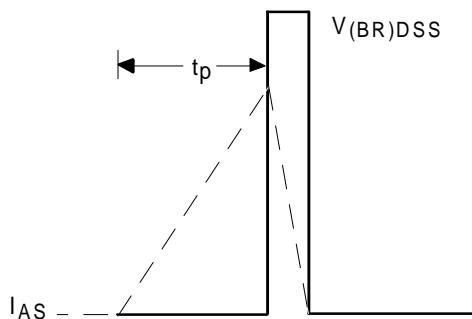


Fig 12b. Unclamped Inductive Waveforms

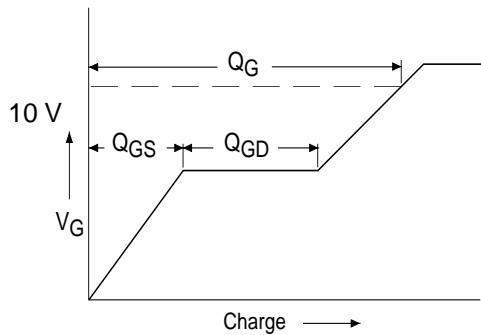


Fig 13a. Basic Gate Charge Waveform

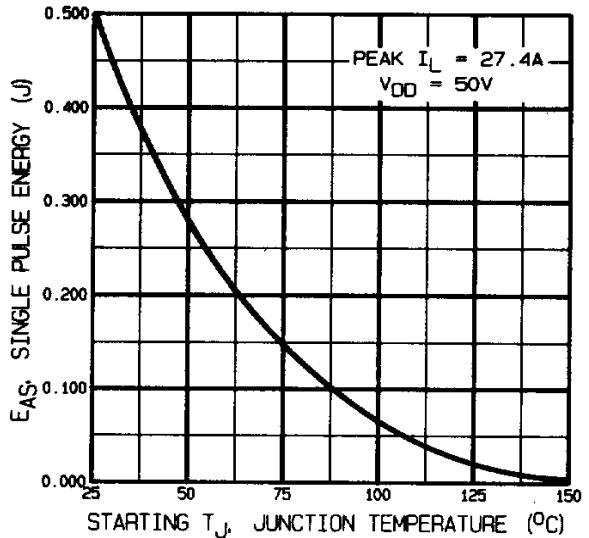


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

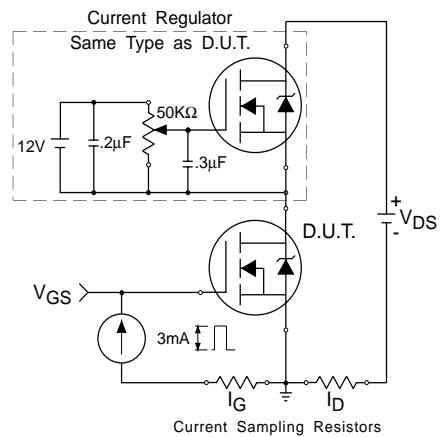
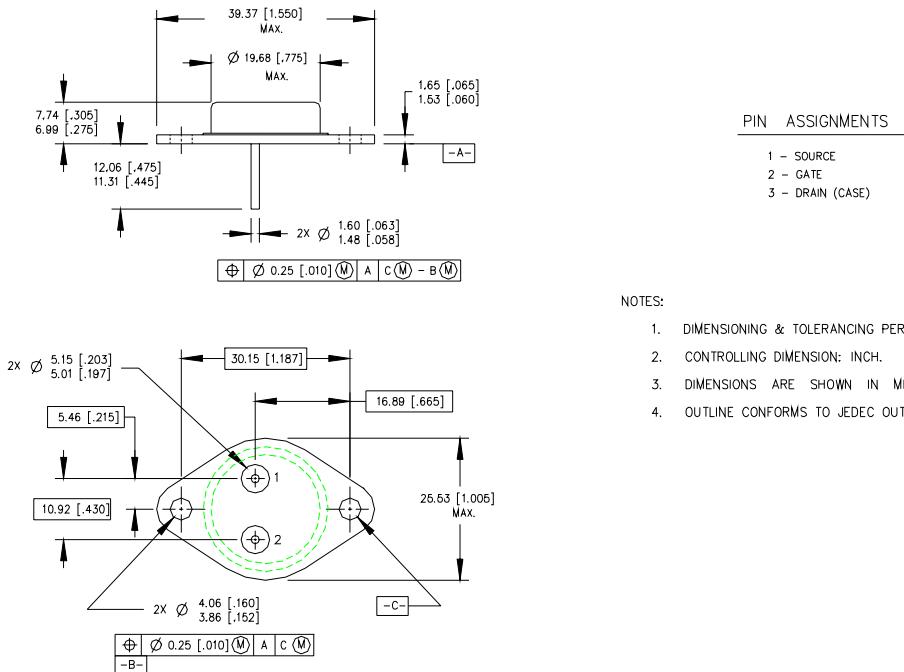


Fig 13b. Gate Charge Test Circuit

Foot Notes:

- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
- ② V_{DD} = 50V, starting T_J = 25°C,
Peak I_L = 30A,
- ③ I_{SD} ≤ 30A, di/dt ≤ 190A/μs,
V_{DD} ≤ 200V, T_J ≤ 150°C
Suggested RG = 2.35 Ω
- ④ Pulse width ≤ 300 μs; Duty Cycle ≤ 2%

Case Outline and Dimensions —TO-204AE (Modified TO-3)



International
IR Rectifier

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105

IR EUROPEAN REGIONAL CENTRE: 439/445 Godstone Rd, Whyteleafe, Surrey CR3 OBL, UK Tel: ++ 44 (0)20 8645 8000

IR CANADA: 15 Lincoln Court, Brampton, Ontario L6T3Z2, Tel: (905) 453 2200

IR GERMANY: Saalburgstrasse 157, 61350 Bad Homburg Tel: ++ 49 (0) 6172 96590

IR ITALY: Via Liguria 49, 10071 Borgaro, Torino Tel: ++ 39 011 451 0111

IR JAPAN: K&H Bldg., 2F, 30-4 Nishi-Ikebukuro 3-Chome, Toshima-Ku, Tokyo 171 Tel: 81 (0)3 3983 0086

IR SOUTHEAST ASIA: 1 Kim Seng Promenade, Great World City West Tower, 13-11, Singapore 237994 Tel: ++ 65 (0)838 4630

IR TAIWAN: 16 Fl. Suite D. 207, Sec. 2, Tun Haw South Road, Taipei, 10673 Tel: 886-(0)2 2377 9936

Data and specifications subject to change without notice. 01/01